

Search Notes

Application/Control No.

10/022,622

Examiner

Feben M. Haile

Applicant(s)/Patent under
Reexamination

KIM, KI-TAEK

Art Unit

2663

SEARCHED

Class	Subclass	Date	Examiner
370	389	2/3/2006	FH
370	395.1	2/3/2006	FH
370	395.7	2/3/2006	FH
370	395.71	2/3/2006	FH
370	412	2/3/2006	FH
370	413	2/3/2006	FH
370	395.6	2/3/2006	FH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search: atm, cell, fifo, SOC, synchronization, buffer, memory, queue, storage, utopia, discard, remove	2/3/2006	FH